


<b>Search Notes</b>  	<b>Application/Control No.</b>  10585832	<b>Applicant(s)/Patent Under Reexamination</b>  TESHIROGI ET AL.
	<b>Examiner</b>  Shih-Chao Chen	<b>Art Unit</b>  2821

SEARCHED			
Class	Subclass	Date	Examiner
343	711, 700MS, 895	3/5/09	CHEN

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	3/5/09	CHEN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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